


Search Notes 	Application/Control No. 10574600	Applicant(s)/Patent Under Reexamination AKAHORI ET AL.
	Examiner Baker, David S	Art Unit 2884

SEARCHED			
Class	Subclass	Date	Examiner
250	336.1	16 NOV 08	DSB
250	370.01	16 NOV 08	DSB
250	370.14	16 NOV 08	DSB

SEARCH NOTES			
Search Notes		Date	Examiner
See attached EAST Search History		16 NOV 08	DSB
Consultation: Examiner Christine Sung AU 2884		16 NOV 08	DSB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
ALL	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
250	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
378	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB
600	ALL; Search Terms: "(voltage WITH divid\$3).clm. AND resistor.clm. AND serial\$3.clm. AND semiconductor.clm. AND electrode.clm."	21 JUL 08	DSB

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